

**Notice of References Cited**

Application/Control No.

10/582,594

Applicant(s)/Patent Under  
Reexamination  
BEIER ET AL.

Examiner

Patrick F. O'Reilly III

Art Unit

3749

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2,562,918 A	08-1951	HYNES WILLIAM M	454/74
*	B	US-3,177,679 A	04-1965	QUICK DESMOND F J; et. al.	62/402
*	C	US-4,149,389 A	04-1979	Hayes et al.	62/79
*	D	US-RE32,100 E	04-1986	Rannenber, George C.	62/80
*	E	US-5,299,763 A	04-1994	Bescoby et al.	244/118.5
*	F	US-5,906,111 A	05-1999	Lui, Clarence	62/402
*	G	US-5,934,083 A	08-1999	Scherer et al.	62/79
*	H	US-6,250,097 B1	06-2001	Lui et al.	62/402
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2398864 A	09-2004	United Kingdom	AXE et al.	B64D 13/08
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

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